What are the best strategies to collect high-quality, publication-ready data for absolute configuration determination from samples with low anomalous signal? Should the focus be on exposure time or multiplicity? Or should it be both? Long gone is the era of days- or weeks-long data collections for good quality structures. Even though routine single crystal X-ray diffraction data can now be collected in a few hours or less, finding the perfect ratio of experiment length to data quality can still seem daunting. Using select examples, this talk will focus on methods to plan effective and complete strategies, optimize data collection time and highlight strategies to improve precision in absolute configuration determination experiments.